Direct measurement of the ¹²C(¹²C,α)²⁰Ne cross section at stellar energies

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The carbon fusion reactions in the Universe



Ignition in type Ia supernovae







Uncertain cross section at stellar energies



- Large Uncertainty in experimental results within the Gamow window
- Different predictions between models and indirect methods
 - Unknow resonances: Need better
 selection T=0, J^π=0⁺,2⁺? lack of
 information of angular
 distribution

Beck, Mukhamedzhanov and Tang, Eur. Phys. J. A (2020) 56:87 Mukhamedzhanov, Eur. Phys. J. A (2022) 58:71 Tang & Ru, EPJ Web of Conferences 260, 01002 (2022)

Uncertain cross section at stellar energies



Taniguchi & Kimura, Phys. Lett. B 849 (2024)

Why we focus on the g.s. channels



How to study this reaction?

 ≻ Charged-particle measurement low statistics huge backgrounds
 ≻ γ-ray measurement sensitive probe

1634keV, 440keV cannot study the g.s. channels

> Particle- γ coincidence

suppress backgrounds cannot study the g.s. channels



The accelerator and detectors

Low Energy Accelerator Facility (LEAF)



Accelerator platform:

- up to $100 \text{ puA}(\text{Spillane: 40puA}) \text{ C}^{2+}$
- Energy spread < 0.2%
- Energy for ¹²C beam: 4 8 MeV

Energy calibration by nuclear reaction resonances:

- ${}^{27}\text{Al}(p,\gamma){}^{28}\text{Si: Er} = 405.5 \text{ keV}$
- $H(^{15}N,\alpha\gamma)^{12}C$: Er = 6398 keV





Christain Iliadis, Nuclear Pyhsics of Stars



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Detection system:

- **TPC:** Ultra sensitive tracking detector
- Si: record energy information



Beam







Carbon targets

• The selection of carbon target

high-purity: very little ¹³C, Li, Be, B...
 very thick target, unsensitive to target declination
 stable, not easily destroyed by beam
 good conduction for heat





Analysis: Ecm=2.75MeV with graphite

Particle identification



✓ Particle identification via energy-loss in TPC and energy in silicons

Analysis: Ecm=2.75MeV with graphite



Particle identification via energy-loss in TPC and energy in silicons
 Tracing the origin of tracks to suppress natural backgrounds



The Q-values for this reaction were calculated from the angles and energies of ejections

Alpha peaks can be found with backgrounds

spectra w/o tracking









Analysis: Ecm=2.40MeV with HOPG

Very low energy : Long-time measurement brings **more backgrounds** but **events of interests are even fewer**



No signals in the natural alpha backgrounds

It's difficult for direct measurements at such low energies

Analysis: Ecm=2.40MeV with HOPG

Very low energy : Long-time measurement brings **more backgrounds** but **events of interests are even fewer**



The TPC+Si systerm is still effective in very-low-energy measurement!

Angular Distribution Results

The detector solid angle coverage θ : 116°-151°(c.m.) / 100°-140° (lab.) Differential thick target yield dYield/d Ω can be calculated



Similar methods are applied to obtain the angular distribution from $E_{cm} = 2.4 \text{MeV}$ to $E_{cm} = 3.5 \text{MeV}$

- First high-precision angular distribution measurement of ¹²C(¹²C, α₀)²⁰Ne channel below E_{cm} = 3.0MeV
- ➤ The J^π of resonances can be determined with the information of angular distribution



Summary

Direct measurement of ¹²C+¹²C (charged particle measurement)

- First direct measurement of a₀ channel below 2.5 MeV indicates new resonances
- Analysis of angular distribution in large energy range
- Complementary to direct measurements (eg. gamma ray, particle-gamma) of other reaction channels
- New reaction rate ~ CF88/3

Indirect+Direct measurements +theoretical extrapolation are essential

- Direct measurements will help theories(eg. AMD) and indirect measurements (THM, ²⁴Mg(a,a'))to provide a more reliable prediction
- Experiments for lower energies and more channels are needed
- Collaboration will end up with better science!



CARbon FUSion Experiment (CARFUSE) @LEAF, IMP



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Backups

Backup

Legendre polynomials can be used to describe the variation of the differential cross section with respect to the angle.

$$\frac{d\sigma}{d\Omega}(\theta_{c.m.}) = \sum (b_l P_l(\cos\theta_{c.m.}))$$

n	$P_n(x)$
0	1
1	x
2	$\frac{1}{2}(3x^2-1)$
3	$\frac{1}{2}(5x^3 - 3x)$
4	$\frac{1}{8}(35x^4 - 30x^2 + 3)$
5	$\frac{1}{8}(63x^5 - 70x^3 + 15x)$
6	$\frac{1}{16}(231x^6 - 315x^4 + 105x^2 - 5)$
7	$\frac{1}{16}(429x^7 - 693x^5 + 315x^3 - 35x)$
8	$\frac{1}{128}(6435x^8 - 12012x^6 + 6930x^4 - 1260x^2 + 35)$



Detectors



- Charged particles ionize electrons from working gas(mainly He+CO₂+Ar/Kr)
- Electrons drift to the micro MEGAS and are multiplied, the position and signal amplitude are recorded

Data analysis

Event selection





- By track tracing, we know where this track comes from
- Cosmos rays and natural background are thrown

Low Energy Accelerator Facility (LEAF)



termina

- Beam intensity up to **<u>100 puA</u>** on target(Spillane: 40puA) •
- Energy spread < 0.2% ٠

ion source

Energy for ¹²C beam: 4 - 8 MeV





Analysis: Ecm=2.40MeV with HOPG



Preliminary results Thick-target yield

Angular distribution

Thick target can be seen as an accumulation of an infinite number of very thin targets

So



yield of thin layer of target with thickness of D:

 $Y = N_{\rm V}\sigma D = N_{\rm s}\sigma$

(Nv: nucleus number density)

total yield for target of thickness D:

$$Y = N_{\rm V} \int_0^D \sigma(E) dx = N_{\rm V} \int_0^{R(E_0)} \sigma(E) dx$$
$$= N_{\rm V} \int_{E_0}^0 \sigma(E) \frac{dE}{(dE/dx)}$$

 $Y(E_0) = N_V \int_0^{E_0} \left[\sigma(E) \left(- \left(\frac{dE}{dx} \right) \right] dE$

Stopping power

For this experiment, we used infinite thick target with so high beam intensity

Preliminary results

Thick-target yield

Angular distribution

Cross section of reactions can be obtained by differentiating the yield of thick target



When $\Delta E \rightarrow 0$ ($\Delta x \rightarrow 0$), $E_{eff} \rightarrow E_0$, So:

$$\sigma(\mathbf{E}) = \left(-\frac{1}{N_v}\frac{dE}{dx}\right)\frac{\partial \text{Yield}}{\partial \mathbf{E}}$$

This is how we calculated the cross section from the fit-curve of thick target yield